L Number	Hits	Search Text	DB	Time stamp
10	645	semiconductor same defective same reference$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/30 14:36
11	12	semiconductor same defective same reference$1 same marking$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/30 14:34
12	357	semiconductor same defective same mark$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/30 14:37
13	453	semiconductor same (defective near5 mark$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/30 14:37
14	23	semiconductor same (defective near5 mark$4) same reference$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/30 14:39
15	3	semiconductor same (defective near10 mark$4 near10 character$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/30 14:39